

SONY**CXB1107Q/Q-Y**

T-46-07-08

Decision Circuit with Differential I/O**Description**

The CXB1107Q is an ECL ultra high speed monolithic Decision Circuit, which contains a D Flip-Flop with High Gain Slicer at the input stage.

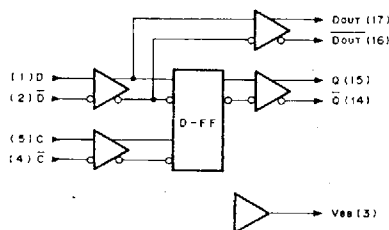
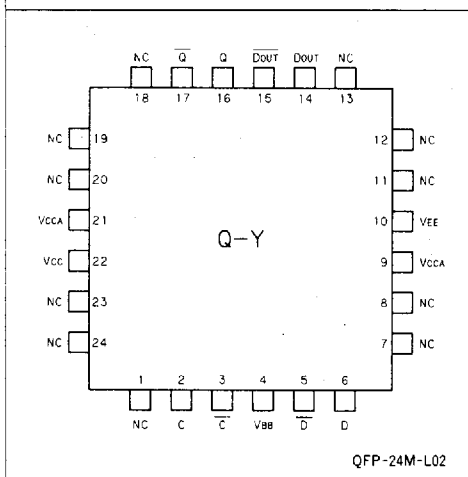
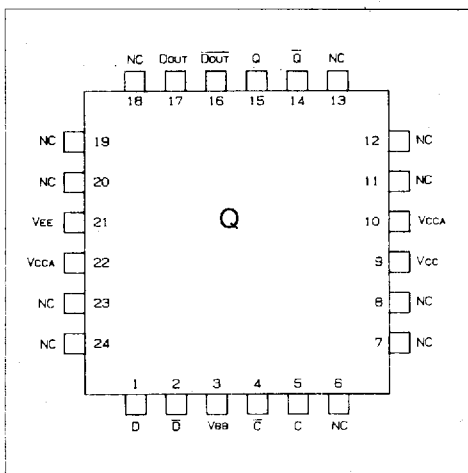
Differential data input is amplified by the High Gain Slicer and stored in the D Flip-Flop at the positive transition of the Clock. The stored data is held at Q and $\bar{Q}$ pins until the next positive transition of the Clock occurs. The Clock input has differential input pins C and $\bar{C}$. Built-in reference voltage is provided at V_{BB} pins to facilitate the use of single input operation.

Features

- Typical AC characteristics: Clock rate up to 3.2GHz
Clock rate up to 2.3GHz at an input level of 50mV
- Differential Data and Clock inputs
- Internal pull down resistors on input pins to maintain logic LOW level with the pins left open
- ECL 100K compatible I/O levels

Pin Names

D, $\bar{D}$	Data input
C, $\bar{C}$	Clock inputs (positive edge trigger)
Q, $\bar{Q}$	Data output
DOUT, $\bar{DOUT}$	Buffered input data outputs
V_{BB}	Reference voltage output
VCC	Circuit ground
VCCA	Circuit ground for outputs
VEE	Negative power supply

Logic Symbol**Pin Assignment**

QFP-24M-L02

SONY

CXB1107Q/QY

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DC Characteristics

 $V_{EE} = -4.5 \pm 0.3V$, $V_{CC} = V_{CCA} = GND$, $V_{TT} = -2.0V$, $T_C = 0^\circ C$ to $+85^\circ C$

Item	Symbol	Test Condition	Min.	Typ.	Max.	Unit
Power supply current	I_{EE}		-116	-85	-59	mA
Input voltage range	V_{IN}		-2.0	-1.3	-0.5	V
Min. Decision voltage	V_D	$f_{CLOCK} = 1.8GHz$			50	mVpp

Note: Other DC characteristics; See pages 3-3 and 3-4.

AC Characteristics

 $V_{EE} = -4.5 \pm 0.3V$, $V_{CC} = V_{CCA} = GND$, $V_{TT} = -2.0V$, $T_C = 0^\circ C$ to $+85^\circ C$, $R_T = 50\Omega$ to V_{TT}

Item	Symbol	Input	Output	Test Condition	Min.	Typ.	Max.	Unit
Propagation delay time	T _{PLH}	C	Q		460	610	770	ps
	T _{PHL}				440	590	750	
	T _{PLH}	D	D _{OUT}		420	570	730	
	T _{PHL}				400	550	710	
Set up time	T _S	D, C	Q		220			
Hold time	T _H	C, D			120			
Max. Clock frequency	f _{MAX}	D		V _{in} =50mV _{pp}	1.8	2.3		GHz
				V _{in} =800mV _{pp}	2.6	3.2		
Rise time	T _{TLH}	C		20% to 80%		220	280	ps
Fall time	T _{THL}					170	220	

Note: AC test circuit; See pages 4-3, 4-4 and 4-5.

Truth Table

Input		Output	
D	C	Q	DOUT
L	L	Hold	L
H	L	Hold	H
L	J	L	L
H	J	H	H
L	H	Hold	L
H	H	Hold	H

Note: H; HIGH voltage level

L; LOW voltage level

J; Positive transition edge

Hold; Means no-change in the output

Package Data

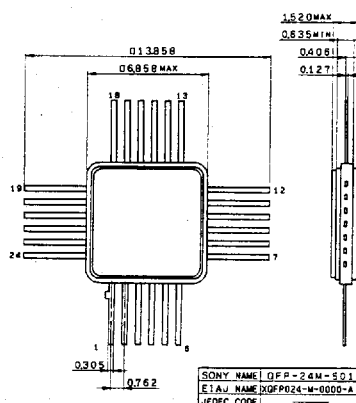
T-90-20

Package Outline

Unit: mm

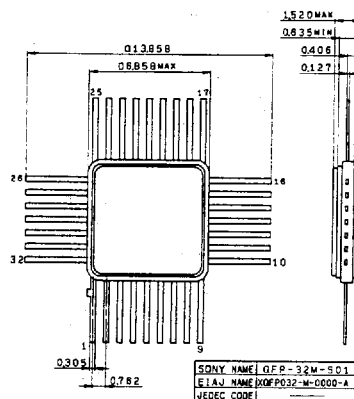
24pin QFP (QFP-24M-S01)

24pin QFP (Metal) 0.3g



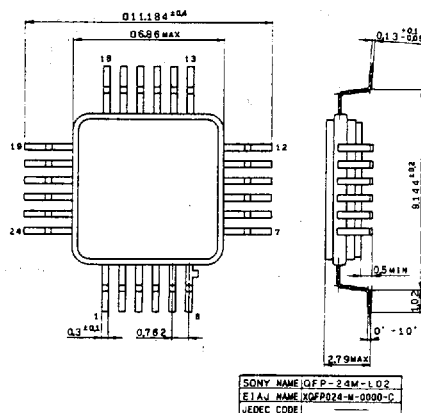
32pin QFP (QFP-32M-S01)

32pin QFP (Metal) 0.2g



24pin QFP (QFP-24M-L02)

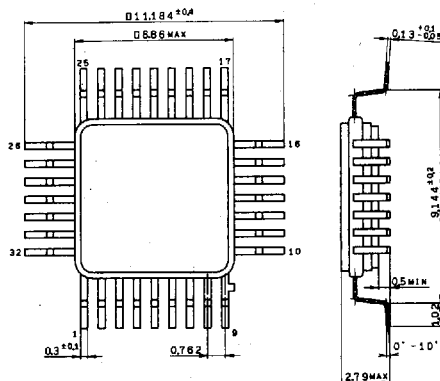
24pin QFP (Metal) 0.3g



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32pin QFP (QFP-32M-L02)

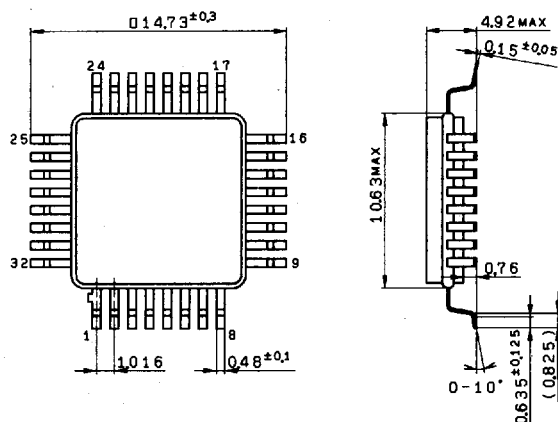
32pin GFP (Metal) 0.2g



SONY NAME	QFP-32M-L02
EIAJ NAME	XGFP032-M-0000-C
JEDEC CODE	

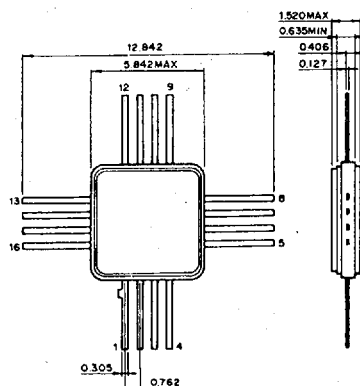
32pin QFP (QFP-32C-L01)

32pin GFP (Ceramic)



SONY NAME	QFP-32C-L01
EIAJ NAME	XGFP032-G-0000-A
JEDEC CODE	

16pin QFP



Package Data

Package Data		Page
1. 16 pin QFP		6-3
2. 24 pin QFP		6-3
3. 32 pin QFP		6-3
4. 24 pin QFP with formed lead		6-4
5. 32 pin QFP with formed lead		6-4

Package Data

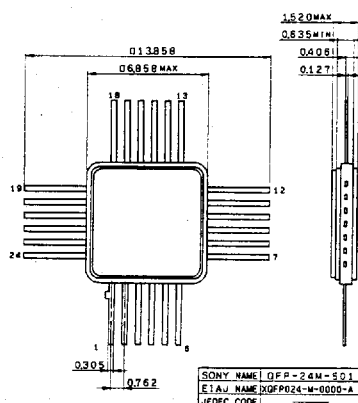
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Package Outline

Unit: mm

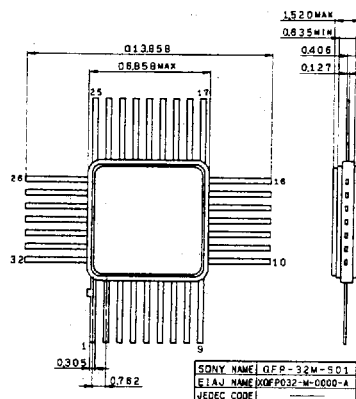
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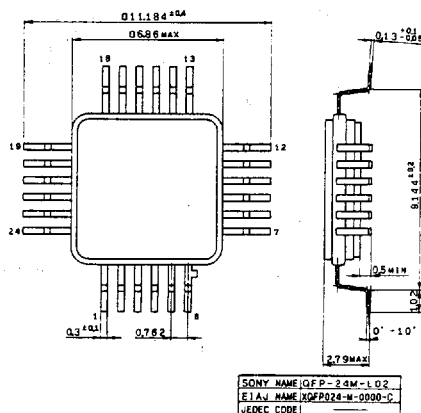
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32pin QFP (Metal) 0.2g



24pin QFP (QFP-24M-L02)

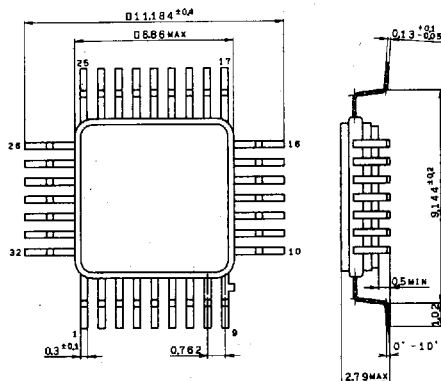
24pin QFP (Metal) 0.3g



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32pin QFP (QFP-32M-L02)

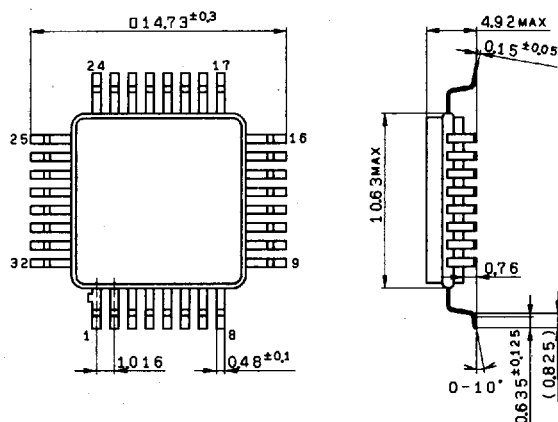
32pin GFP (Metal) 0.2g



SONY NAME	QFP-32M-L02
EIAJ NAME	XGFP032-M-0000-C
JEDEC CODE	

32pin QFP (QFP-32C-L01)

32pin GFP (Ceramic)



SONY NAME	QFP-32C-L01
EIAJ NAME	XGFP032-G-0000-A
JEDEC CODE	

16pin QFP

